

<b>Notice of References Cited</b>	Application/Control No. 09/555,578	Applicant(s)/Patent Under Reexamination KURIYAMA ET AL.	
	Examiner Brian P. Egan	Art Unit 1772	Page 1 of 1

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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	B	US-4,550,683	11-1985	Jones	118/505
	C	US-4,444,839	04-1984	Dudzik et al.	428/336
	D	US-Romagnoli	11-1977	Romagnoli	206/216
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	K	US-			
	L	US-			
	M	US-			

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**NON-PATENT DOCUMENTS**

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	U	On the Distribution of Mass, Thickness, and Density in Paper, Dodson et al., June 6, 2000.
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\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.